

Search Notes

Application/Control No.

10/767,767

Examiner

Thomas D. Lee

Applicant(s)/Patent and
Reexamination

OGAWA, HIDEHIKO

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
358	1.15, 402, 440	11/22/2005	TDL
379	100.01	11/22/2005	TDL
379	100.08	11/22/2005	TDL
379	100.13	11/22/2005	TDL
379	100.17	11/22/2005	TDL
updated		5/9/2006	TDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference Search Printout		5/9/2006	TDL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR